



Introduction

Economic probe table E series probe table has excellent mechanical system, stable structural performance, ergonomic design, more convenient operation, support multi-function upgrade, more product functions. The products are mainly used in the manufacturing and research fields of integrated circuit, LED, LCD, solar cell and other industries.

Application Direction

Chip and LD/LED/PD test, electrode /PAD test over 1 micron, PCB/ package device test, MATERIAL/device IV/CV characteristic test, high frequency test, radio frequency test, etc

Product Feature

- High cost performance configuration, affordable price
- Ergonomic design, convenient and comfortable to operate
- Leading internal anti - shock system device, more stable operation
- Compatible with high power metallographic microscope for fine adjustment and movement
- Precise screw drive structure, high precision motion system
- No backtrip difference design, accurate positioning
- Coaxial drive chuck, high moving precision
- Support for loading upgrade

Model	SE-4	SE-6	SE-8	SE-12	
Dimension	L: 580mm* W: 620mm* H: 730mm	L: 640mm* W: 700mm* H: 730mm	L: 660mm* W: 660mm* H: 700mm	L: 1030mm* W: 820mm* H: 730mm	
Weight (about)	70KG	80KG	85KG	180KG	
Electricity Demand	220VC,50~60Hz				
Chuck	Size & Rotation angle	4", 360° Rotation	6", 360° Rotation	8", 360° Rotation	12", 360° Rotation
	X-Y Travel Range	4" * 4"	6" * 6"	8" * 8"	12" * 12"
	Z Travel Range	6mm (Fast switching) / 6mm (Fine-tune)			
	Moving Resolution	10μm			
	Sample fixed mode	Vacuum adsorption			
	Electrical design	Electrical Floating with Banana plug adapter, can be used as a backside electrode			
Platen	U Shape	6 micropositioners available	8 micropositioners available	10 micropositioners available	12 micropositioners available
Microscope	Moving range	X-Y : 2" * 2", Z : 50.8mm			
	Moving Resolution	1um			
	Switching lens mode	Microscope Manually Tilting 30°by Lever			
	Magnification	16~100X/20~4000X			
	Lens specification	Eyepiece: 10X ; Objective lens : 5X, 10X, 20X, 50X 、 100X(Optional)			
	CCD Pixel	50W (Analog) / 200W (Digital) / 500W (Digital)			
Micropositioner	X-Y-Z Moving range	12mm-12mm-12mm / 8mm-8mm-8mm			
	Mechanical resolution	10μm / 2μm / 0.7μm / 0.1μm			
	Current leakage accuracy	10pA / 100fA (when with Shielding Box)			
	Cable connectors	Banana head / Crocodile clip / Coaxial / Triaxial			
Application	IC/LD/LED/PD test, PCB / Packaged device test, RF test etc.				
Optional Accessories	Microscope tilt mechanism (Tilting 30°Manually by Lever)				Gold-plated chuck
	Microscope pneumatic lifting mechanism				Coaxial / Triaxial chuck
	Laser cutting and repairing				Chuck quick pull-out mechanism
	Probe clamp				Chuck rotation fine adjustment
	Dark field of microscope / DIC / Normarski test, Light intensity / wavelength test interface accessory				Light intensity / wavelength selection
	Liquid crystal leakage analysis package				RF Testing accessories
	High voltage and high current measurement package				Active probe
	Hot chuck				Low current / Capacitance test
	High/Low temprature chuck				intergration of intergral sphere
	Shielding box				Fixture for Fibre optic coupler test
	Special adapter				Fixture of PCB / Package test options
	Vibration free table				Special Custom design
	Charancteristic	1. Gantry design of the Microscope.			
2. The Microscope can be tilted or pneumatic lifted to change objective lens easily.					
3. Can be upgraded to do RF, high current testing and laser repair applications.					
4. High moving accuracy.					